

Manual Supplement

Manual Title:	1652C/1653B/1654B Users Supplement Issue:	2	
Print Date:	September 2010	Issue Date:	10/11
Revision/Date:		Page Count:	2

This supplement contains information necessary to ensure the accuracy of the above manual. This manual is distributed as an electronic manual on the following CD-ROM:

CD Title:	1652C/1653B/1654B
CD Rev. & Date:	9/2010
CD PN:	3798444

Change #1, 56800

On page 3, add the following bullet:

- **Do not use in CAT III or CAT IV environments without the protective cap installed. The protective cap decreases the possibility of arc flash caused by short circuits.**

On page 6, under *Operating the Tester Using the Rotary Switch*, add the following:

Warning


Do not use in CAT III or CAT IV environments without the protective cap installed. The protective cap decreases the exposed probe metal to <4mm. This decreases the possibility of arc flash from short circuits.

On page 45, under *General Specifications*, add the following to the Safety section:

Complies with EN/IEC 61010-031:2002+A1:2008.


Change #2, 59912

On page 18, Table 8, replace row 2 with:

	Extended documentation mode. Simultaneously press the Power button and the Up cursor key (1654B only). Additional information is stored with an insulation test result (P/P, P/N, P/E, N/E) and with a continuity test result (R1+R2, R2, r1, r2, rn).
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
On page 20, replace the **Extended Documentation Mode section** with:

Extended Documentation Mode


In the Extended Documentation mode (1654B only), the Tester stores the measurement result with the measurement location: P/P, P/N, P/E or N/E. You can select the information before or after the measurement with . The definitions are: P/P = L, P/N = L-N, P/E = L-PE, N/E = N-PE.

On page 22, replace **Extended Documentation Mode section** with:

Extended Documentation Mode




In the Extended Documentation mode (1654B only), the Tester stores the measurement result with the measurement location: R1+R2, R2, r1, r2 or rn. You can select the information before or after the measurement with . The definitions are: R1+R2 = Rx1/2, R2 = R/2, r1 = x1, r2 = /2, rn = x5.

On pages 24 and 26, replace step 4 with:




4. For the 1654B only, press  to select between Ω and $m\Omega$ resolution for the test results. The $m\Omega$ resolution test takes between 30 and 60 seconds to complete.

On page 29 replace the last two bullets in step 4 and the Note with:

1654B only:




-  – Smooth-DC current to test type B RCD
-   – Delayed response to S-type B (time delayed smooth-DC current RCD)

Note

For RCD type B () or S-type B ( ) , you must test with both phase settings and measure the trip current.

On page 33, replace the last two bullets in step 3:

1654B only:

-  – Smooth-DC current to test type B RCD
-   – Delayed response to S-type B (time delayed smooth-DC current RCD)

On page 52, replace the second Table with:

Range	Resolution	Accuracy ^[1]
10 Ω ^[2]	0.001 Ω	Hi Current mΩ mode: ±(2 % + 15 digits)
20 Ω	0.01 Ω	No Trip mode: ±(3 % + 6 digits)
		Hi Current mode: ±(2 % + 4 digits)
200 Ω	0.1 Ω	No Trip mode: ±(3 %)
		Hi Current mode: ±(2 %)
2000 Ω	1 Ω	±6 % ^[3]
Notes [1] Valid for resistance of neutral circuit <20 Ω and up to a system phase angle of 30 °. Test leads must be zeroed before testing. [2] 1654B only. [3] Valid for mains voltage >200 V.		